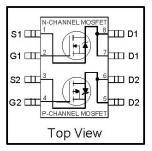
International Rectifier

IRF7309PbF

HEXFET® Power MOSFET

- Generation V Technology
- Ultra Low On-Resistance
- Dual N and P Channel Mosfet
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching
- Lead-Free

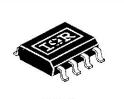


	N-Ch	P-Ch			
V _{DSS}	30V	-30V			
R _{DS(on)}	0.050Ω	0.10Ω			

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design for which HEXFET Power MOSFETs are well known, provides the designer with an extremely efficient device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra-red, or wave soldering techniques. Power dissipation of greater than 0.8W is possible in a typical PCB mount application.



SO-8

Absolute Maximum Ratings

	Parameter	M	Units	
		N-Channel	P-Channel	
I _D @ T _A = 25°C	10 Sec. Pulse Drain Current, VGS @ 10V	4.7	-3.5	Α
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	4.0	-3.0	Α
I _D @ T _A = 70°C	Continuous Drain Current, VGS @ 10V	3.2	-2.4	Α
I _{DM}	Pulsed Drain Current ①	16	-12	Α
P _D @T _A = 25°C Power Dissipation (PCB Mount)**		,	W	
Linear Derating Factor (PCB Mount)**		0.	W/°C	
V _{GS} Gate-to-Source Voltage		±	V	
d∨/dt	Peak Diode Recovery dv/dt 2	6.9	-6.0	V/ns
T _{J,} T _{STG} Junction and Storage Temperature Range		-55 to	°C	

Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
R _{OJA}	Junction-to-Amb. (PCB Mount, steady state)**	-		90	°C/W

^{**} When mounted on 1" square PCB (FR-4 or G-10 Material).

For recommended footprint and soldering techniques refer to application note #AN-994.

1

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter			Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	N-Ch		-	I	V	$V_{GS} = 0V, I_{D} = 250\mu A$	
▼(BR)D55	Brain-to-Cource Breakdown Volkage	P-Ch	-30	-3	_	V	$V_{GS} = 0V$, $I_D = -250\mu A$	
ΔV _{(BR)DSS} /ΔT _J	Breakdown Voltage Temp. Coefficient	N-Ch	_	0.032	1	V/°C	Reference to 25°C, b = 1mA	
TA(RK)DSS(TI)	Breakdown voltage Temp. Obenicient	P-Ch	1/2 /	0.037		V/ C	Reference to 25°C, b = -1mA	
		N-Ch	_	_	0.050		V _{GS} = 10V, I _D = 2.4A 3	
D	Static Drain-to-Source On-Resistance	IN-CII	-	-5	0.080	۱ ۵	V _{GS} = 4.5V, I _D = 2.0A 3	
R _{DS(ON)}	Static Dialit-to-Source Off-Kesistance	P-Ch	D Ck	-5	0.10	Ω	V _{GS} = -10V, I _D = -1.8A 3	
		F-CII	_	_	0.16		V _{GS} = -4.5V, I _D = -1.5A ③	
V	Gate Threshold Voltage	N-Ch	1.0	_	Ī		$V_{DS} = V_{GS}, I_{D} = 250\mu A$	
$V_{GS(th)}$	Gate Threshold Voltage	P-Ch	-1.0	_	_	V	V _{DS} = V _{GS} , I _D = -250µA	
~	Forward Transconductance	N-Ch	5.2	_	_	_	V _{DS} = 15V, I _D = 2.4A 3	
9 fs	Forward Transconductance	P-Ch	2.5	_	-	S	V _{DS} = -24V, I _D = -1.8A 3	
		N-Ch	_	-	1.0		V _{DS} = 24V, V _{GS} = 0V	
il	Drain-to-Source Leakage Current	P-Ch	_		-1.0	١	V _{DS} = -24V, V _{GS} = 0V	
DSS	Diam-to-Source Leakage Current	N-Ch	-	-	25	μA	V _{DS} = 24V, V _{GS} = 0V, T _J = 125°C	
		P-Ch			-25	1	V _{DS} = -24V, V _{GS} = 0V, T _J = 125°C	
lgss	Gate-to-Source Forward Leakage	N-P	_		±100	nA	$V_{GS} = \pm 20V$	
	Total Cata Charge	N-Ch	(d)	_	25		N.O.	
\mathbf{Q}_{g}	Total Gate Charge	P-Ch			25	1	N-Channel	
0	Gate-to-Source Charge	N-Ch	_	_	2.9	1 _	$\begin{aligned} &I_D = 2.6\text{A}, V_{DS} = 16\text{V}, V_{GS} = 4.5\text{V} \\ &\text{G} \\ &\text{P-Channel} \\ &I_D = -2.2\text{A}, V_{DS} = -16\text{V}, V_{GS} = -4.5\text{V} \end{aligned}$	
Q_{gs}	Gate-to-Source Charge	P-Ch			2.9	nC		
0	Gate-to-Drain ("Miller") Charge	N-Ch	_	-3	7.9	1		
Q_{gd}	Gate-to-Diam (Miller) Charge	P-Ch	5-	-	9.0	1		
4 100 €	Turn-On Delay Time	N-Ch	-	6.8	_		1.60	
t _{d(on)}	Turn-On Delay Time	P-Ch	_	11	_	1	N-Channel	
	Rise Time	N-Ch	-	21		1	$V_{DD} = 10V$, $I_D = 2.6A$, $R_G = 6.0\Omega$,	
t _r	Kise i lille	P-Ch	7—	17	_	685045	$R_D = 3.8\Omega$	
■ POSSOBALIS	Turn-Off Delay Time	N-Ch	- T	22	-	ns	(3)	
t _{d(off)}	Turn-On Delay Time	P-Ch	_	25	_	1	P-Channel	
¥	Fall Time	N-Ch	_	7.7	_	1	$V_{DD} = -10V$, $I_D = -2.2A$, $R_G = 6.0\Omega$,	
t _f	rail fille	P-Ch)=	18	-	1	$R_D = 4.5\Omega$	
L _D	Internal Drain Inductace	N-P	_	4.0	_	311	Between lead tip	
L _S	Internal Source Inductance	N-P	_	6.0	-	nH	and center of die contact	
No. of Contract of	Input Capacitance	N-Ch	_	520	-	i	N Channel	
C _{iss}	input Capacitance	P-Ch	_	440	-	1	N-Channel	
<u></u>	Outnut Canacitanas	N-Ch	-	180	_	1	$V_{GS} = 0V, V_{DS} = 15V, f = 1.0MHz$	
Coss	Output Capacitance	P-Ch	12.	200	-	pF	(3)	
_	Bayeres Transfer Conscitones	N-Ch		72	_	1	P-Channel	
C _{rss}	Reverse Transfer Capacitance	P-Ch		93		1	$V_{GS} = 0V, V_{DS} = -15V, f = 1.0MHz$	

Source-Drain Ratings and Characteristics

	Parameter		Min.	Тур.	Max.	Units	Conditions
i i	0 5 0 1/0 1 0 1	N-Ch	-	-	1.8	i i	
Is	Continuous Source Current (Body Diode)	P-Ch		=	-1.8	Α	
	D	N-Ch		J	16		
SM	Pulsed Source Current (Body Diode) ©	P-Ch		Į	-12		
	Diada Farrand Makana	N-Ch	_	J	1.0	V	$T_J = 25^{\circ}C$, $I_S = 1.8A$, $V_{GS} = 0V$ 3
V_{SD}	Diode Forward Voltage		1	J	-1.0	٧	$T_J = 25^{\circ}C$, $I_S = -1.8A$, $V_{GS} = 0V$ 3
4	5 5 ±	N-Ch	_	47	71	ns	N-Channel
t _{rr}	Reverse Recovery Time	P-Ch	_	53	80	113	T _. = 25°C, l ₌ = 2.6A, di/dt = 100A/µs
	D D	N-Ch	-	56	84	пC	P-Channel 3
Q _{rr}	Reverse Recovery Charge	P-Ch	-	66	99	10	$T_{J} = 25^{\circ}C$, $I_{F} = -2.2A$, $di/dt = 100A/\mu s$
ton	Forward Turn-On Time	N-P	Intrir	isic tu	rn-on t	ime is	neglegible (turn-on is dominated by l _S +L _D)

 ${\bf 0}$ Repetitive rating; pulse width limited by max. junction temperature. (See fig. 23)

② N-Channel $I_{SD} \le 2.4A$, $di/dt \le 73A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_{J} \le 150^{\circ}C$ P-Channel $I_{SD} \le -1.8A$, $di/dt \le 90A/\mu s$, $V_{DD} \le V_{(BR)DSS}$, $T_{J} \le 150^{\circ}C$

N-Channel

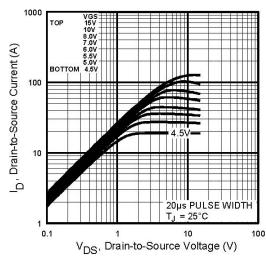


Fig 1. Typical Output Characteristics, T_J = 25°C

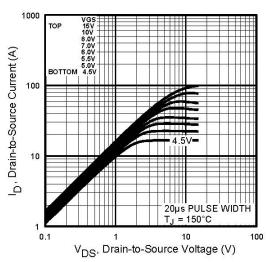


Fig 2. Typical Output Characteristics, $T_J = 150^{\circ}C$

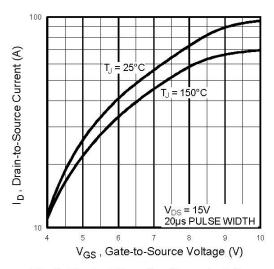


Fig 3. Typical Transfer Characteristics

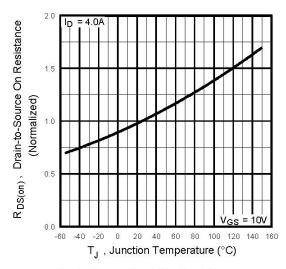


Fig 4. Normalized On-Resistance Vs. Temperature

N-Channel

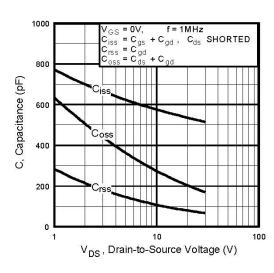


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

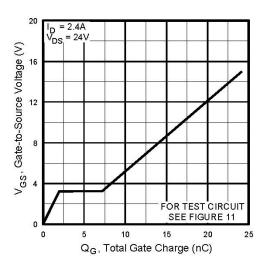


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

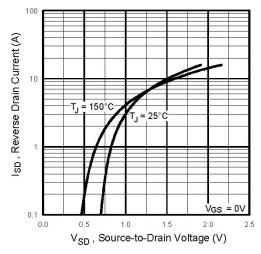


Fig 7. Typical Source-Drain Diode Forward Voltage

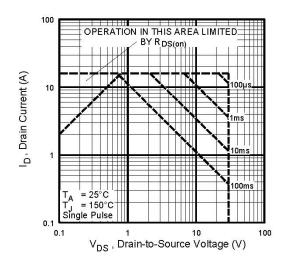


Fig 8. Maximum Safe Operating Area

4.0 (Subject of the first of th

Fig 9. Max. Drain Current Vs. Ambient Temp.

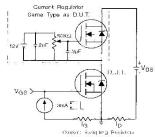


Fig 11a. Gate Charge Test Circuit

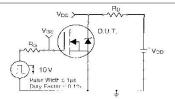


Fig 10a. Switching Time Test Circuit

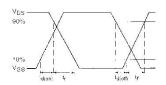


Fig 10b. Switching Time Waveforms

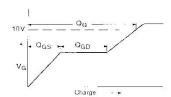


Fig 11b. Basic Gate Charge Waveform

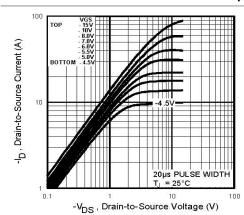


Fig 12. Typical Output Characteristics, Ţ = 25°C

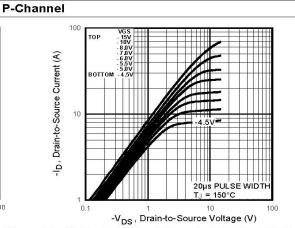


Fig 13. Typical Output Characteristics, Tj = 150°C

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N-Channel

P-Channel

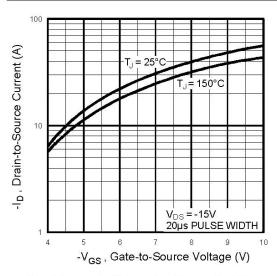


Fig 14. Typical Transfer Characteristics

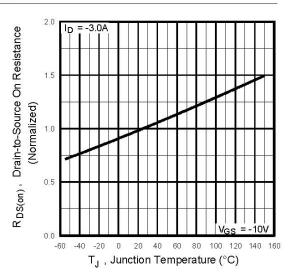


Fig 15. Normalized On-Resistance Vs. Temperature

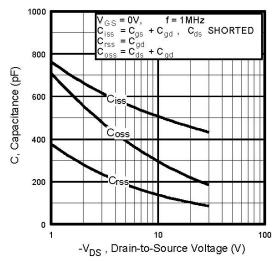


Fig 16. Typical Capacitance Vs. Drain-to-Source Voltage

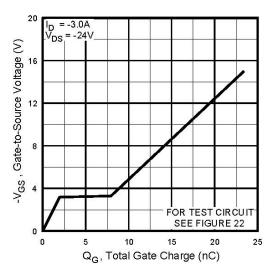


Fig 17. Typical Gate Charge Vs. Gate-to-Source Voltage

P-Channel

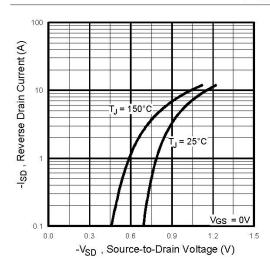


Fig 18. Typical Source-Drain Diode Forward Voltage

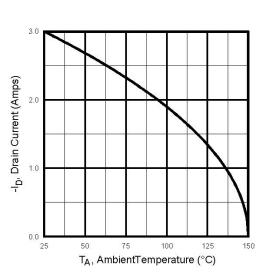


Fig 20. Max. Drain Current Vs. Ambient Temp.

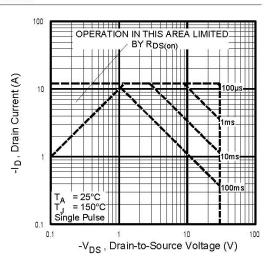


Fig 19. Maximum Safe Operating Area

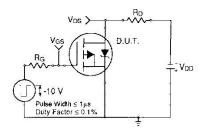


Fig 21a. Switching Time Test Circuit

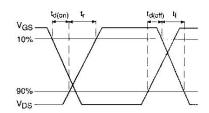


Fig 21b. Switching Time Waveforms

P-Channel

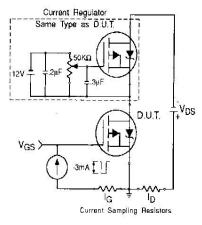


Fig 22b. Gate Charge Test Circuit

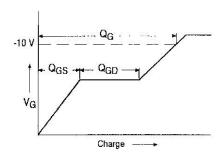


Fig 22b. Basic Gate Charge Waveform

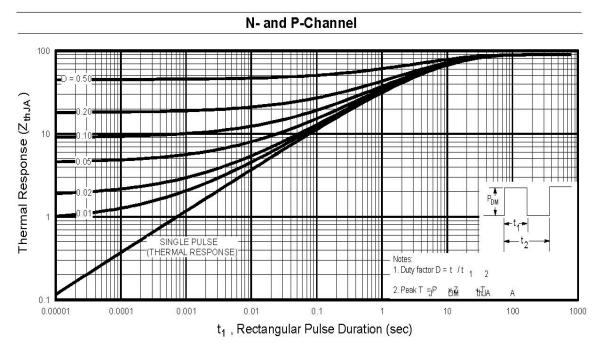
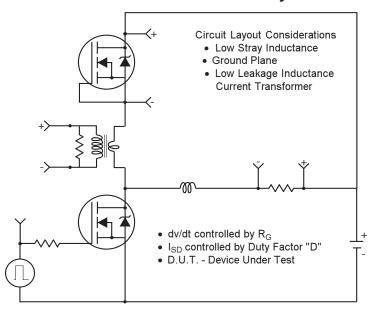
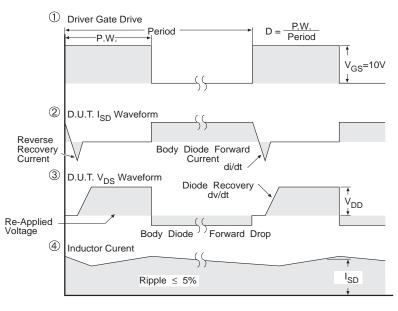


Fig 23. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

Peak Diode Recovery dv/dt Test Circuit



- * Reverse Polarity for P-Channel
- ** Use P-Channel Driver for P-Channel Measurements



*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

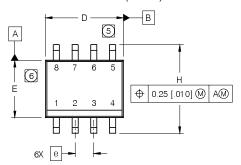
Fig 24. For N and P Channel HEXFETS

International

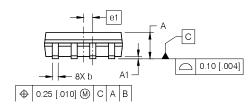
TOR Rectifier

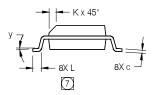
SO-8 Package Details

Dimensions are shown in milimeters (inches)



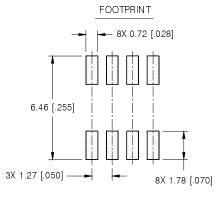
DIM	INC	HES	MILLIMETERS			
DIIW	MIN	MAX	MIN	MAX		
Α	.0532	.0688	1.35	1.75		
A1	.0040	.0098	0.10	0.25		
b	.013	.020	0.33	0.51		
С	.0075	.0098	0.19	0.25		
D	.189	.1968	4.80	5.00		
Е	.1497	.1574	3.80	4.00		
е	.050 B	ASIC	1.27 BASIC			
e 1	.025 B	ASIC	0.635 BASIC			
Н	.2284	2440	5.80	6.20		
K	.0099	.0196	0.25	0.50		
L	.016	.050	0.40	1.27		
У	0°	8°	0°	8°		





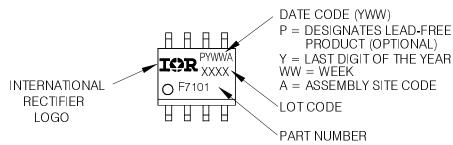
NOTES:

- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: MILLIMETER
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
- (7) DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE

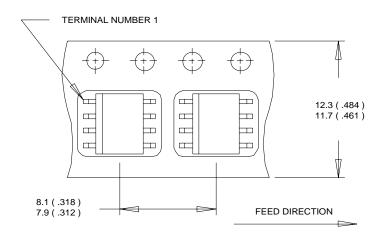


SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

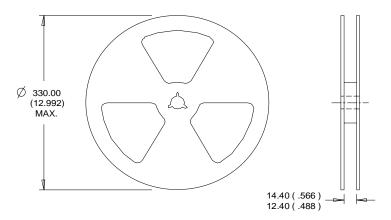


SO-8 Tape and Reel



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

- 1. CONTROLLING DIMENSION : MILLIMETER.
 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice.



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